Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/657,754	KIM, HEE JEAN
Examiner	Art Unit
Tongoc Tran	2134

SEARCHED				
Class	Subclass	Date	Examiner	
380	201-202	4/26/2007	· T T	
380	211,241	4/26/2007	п	
380	278	4/26/2007	π	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	,				
		·	,		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East	4/26/2007	ĪΤ	
Inventor name search	4/26/2007	т	
ACM, IEEE	4/26/2007	π	
East	4/27/2007	т	
·			